Notice of References Cited

Application/Control No. 09/618,102	Reexamination	App. nt(s)/Patent Under Reexamination ORR, RICHARD S.	
Examiner	Art Unit		
Van Kim T. Nguyen	2661	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,108,317	08-2000	Jones et al.	370/320
*	В	US-6,493,330	12-2002	Miya et al.	370/335
*	_ C_	US-6,026,129	02-2000	Ohta et al.	375/332
*	D	US-6,594,286	07-2003	Chen et al.	370/529
*	Ε	US-6,493,334	12-2002	Krzymien et al.	370/342
*	F	US-6,504,883	01-2003	Morimoto et al.	375/343
*	G	US-6,501,955	12-2002	Durrant et al.	455/456.1
*	н	US-6,516,183	02-2003	Hellmark, Leif Martin	455/78
*	ı	US-6,240,081	05-2001	Khalona, Ramon A.	370/342
*	J	US-6,205,167	03-2001	Kamgar et al.	375/134
*	K	US-6,459,723	10-2002	Kim et al.	375/146
*	L	US-6,466,566	10-2002	De Gaudenzi et al.	370/342
*	М	US-6,064,663	05-2000	Honkasalo et al.	370/335

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	ο					
	R					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.